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November 2015

FQD2N60C / FQU2N60C

N-Channel QFET[®] MOSFET 600 V, 1.9 A, 4.7 Ω

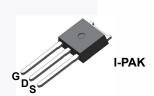
Features

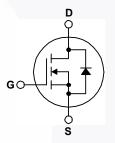
- 1.9 A, 600 V, $R_{DS(on)}$ = 4.7 Ω (Max.) @ V_{GS} = 10 V, I_D = 0.95 A
- Low Gate Charge (Typ. 8.5 nC)
- · Low Crss (Typ. 4.3 pF)
- 100% Avalanche Tested
- RoHS Compliant

Description

This N-Channel enhancement mode power MOSFET is produced using Fairchild Semiconductor's proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance and high avalanche energy strength. These devices are suitable for switched mode power supplies, active power factor correction (PFC), and electronic lamp ballasts.







Absolute Maximum Ratings T_C = 25°C unless otherwise noted.

Symbol	Parameter		FQD2N60CTM / FQU2N60CTU	Unit
V _{DSS}	Drain-Source Voltage		600	V
I _D	Drain Current - Continuous (T _C = 25°C)		1.9	Α
	- Continuous (T _C = 100°C)		1.14	Α
I _{DM}	Drain Current - Pulsed	(Note 1)	7.6	Α
V _{GSS}	Gate-Source Voltage		± 30	V
E _{AS}	Single Pulsed Avalanche Energy (Note 2)		120	mJ
I _{AR}	Avalanche Current (Note 1)		1.9	Α
E _{AR}	Repetitive Avalanche Energy (Note 1)		4.4	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	4.5	V/ns
P_{D}	Power Dissipation (T _A = 25°C)*		2.5	W
	Power Dissipation (T _C = 25°C)		44	W
	- Derate above 25°C		0.35	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150	°C
T _L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C

Thermal Characteristics

Symbol	Parameter	FQD2N60CTM / FQU2N60CTU	Unit	
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case, Max.	2.87		
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (minimum pad of 2 oz copper), Max.	110	°C/W	
	Thermal Resistance, Junction-to-Ambient (* 1 in² pad of 2 oz copper), Max.	50		

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity	
FQD2N60C	FQD2N60CTM	D-PAK	330 mm	16 mm	2500 units	
FQU2N60C	FQU2N60CTU	I-PAK	Tube	N/A	70 units	

Electrical Characteristics $T_C = 25^{\circ}C$ unless otherwise noted.

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
Off Cha	aracteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	600			V
ΔBV_{DSS} / ΔT_{J}	Breakdown Voltage Temperature Coefficient	I _D = 250 μA, Referenced to 25°C		0.6		V/°C
	Zero Gate Voltage Drain Current	V _{DS} = 600 V, V _{GS} = 0 V			1	μΑ
I _{DSS}		V _{DS} = 480 V, T _C = 125°C			10	μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = 30 V, V _{DS} = 0 V			100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	V _{GS} = -30 V, V _{DS} = 0 V			-100	nA
On Cha	racteristics					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$	2.0		4.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = 10 V, I _D = 0.95 A		3.6	4.7	Ω
9 _{FS}	Forward Transconductance	V _{DS} = 40 V, I _D = 0.95 A		5.0		S
	ic Characteristics					
C _{iss}	Input Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$		180	235	pF
C _{oss}	Output Capacitance	f = 1.0 MHz		20	25	pF
C _{rss}	Reverse Transfer Capacitance			4.3	5.6	pF
Switchi	ing Characteristics					
t _{d(on)}	Turn-On Delay Time	$V_{DD} = 300 \text{ V}, I_D = 2 \text{ A},$		9	28	ns
t _r	Turn-On Rise Time	$R_G = 25 \Omega$		25	60	ns
t _{d(off)}	Turn-Off Delay Time			24	58	ns
t _f	Turn-Off Fall Time	(Note 4)	/	28	66	ns
Qg	Total Gate Charge	V _{DS} = 480 V, I _D = 2 A,	-	8.5	12	nC
Q _{gs}	Gate-Source Charge	V _{GS} = 10 V		1.3		nC
Q _{gd}	Gate-Drain Charge	(Note 4)		4.1		nC
Drain-S	Source Diode Characteristics a	nd Maximum Ratings				
I _S	Maximum Continuous Drain-Source Diode Forward Current				1.9	Α
I _{SM}	Maximum Pulsed Drain-Source Diode Forward Current				7.6	Α
V _{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S = 1.9 A			1.4	V
t _{rr}	Reverse Recovery Time	V _{GS} = 0 V, I _S = 2 A,	-	230	- 1	ns
Q _{rr}	Reverse Recovery Charge	dI _F / dt = 100 A/μs		1.0		μС

NOTES

^{1.} Repetitive Rating : Pulse width limited by maximum junction temperature.

^{2.} L = 56 mH, I $_{AS}$ = 2 A, V $_{DD}$ = 50 V, R $_{G}$ = 25 Ω , starting T $_{J}$ = 25°C.

^{3.} $I_{SD} \le 2$ A, di/dt ≤ 200 A/ μ s, $V_{DD} \le BV_{DSS,}$ starting T_J = 25°C.

^{4.} Essentially independent of operating temperature.

Typical Performance Characteristics

Figure 1. On-Region Characteristics

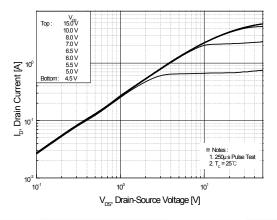


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

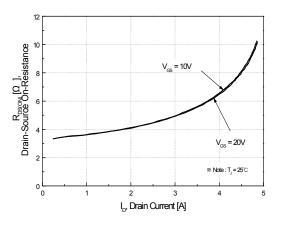


Figure 5. Capacitance Characteristics

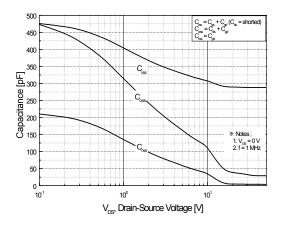


Figure 2. Transfer Characteristics

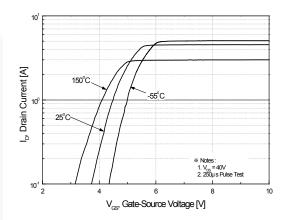


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperatue

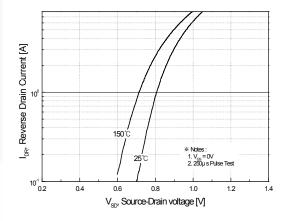
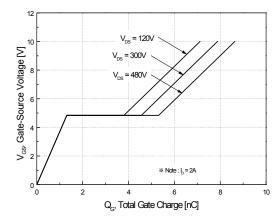


Figure 6. Gate Charge Characteristics



Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

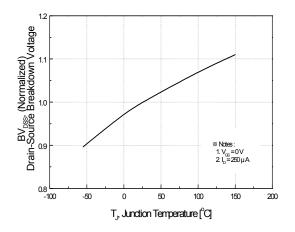


Figure 9. Maximum Safe Operating Area

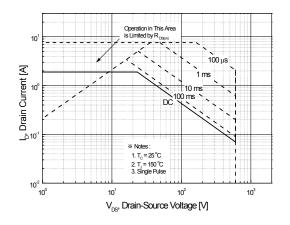


Figure 8. On-Resistance Variation vs. Temperature

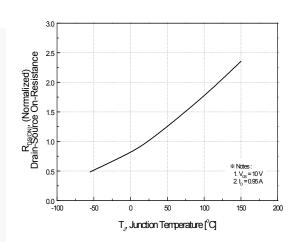


Figure 10. Maximum Drain Current vs. Case Temperature

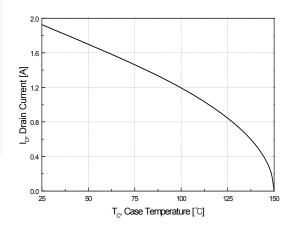


Figure 11. Transient Thermal Response Curve

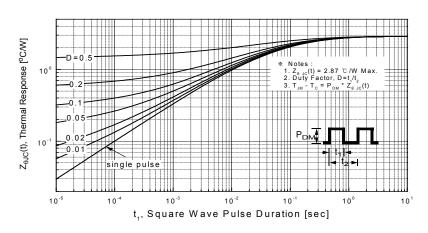


Figure 12. Gate Charge Test Circuit & Waveform

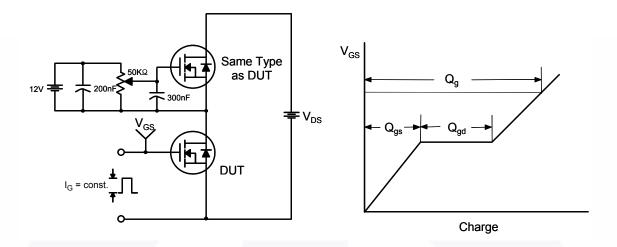


Figure 13. Resistive Switching Test Circuit & Waveforms

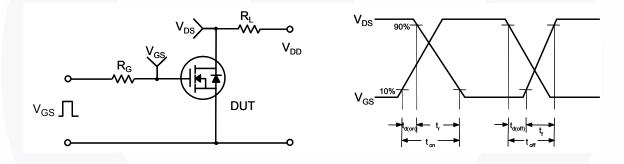
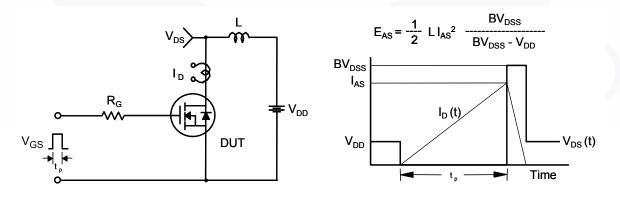


Figure 14. Unclamped Inductive Switching Test Circuit & Waveforms



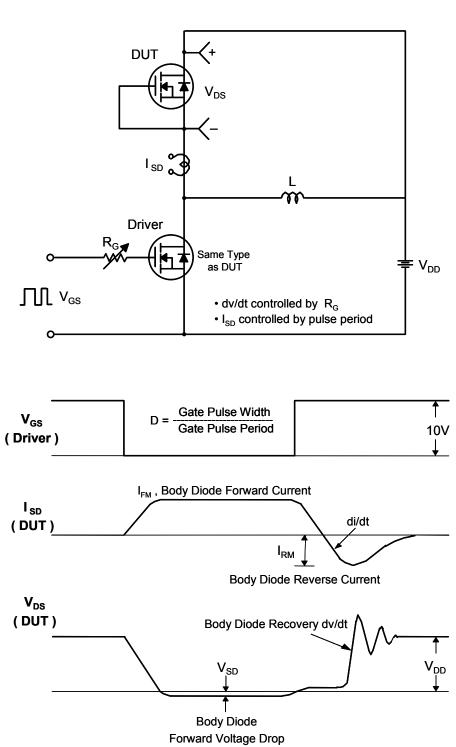
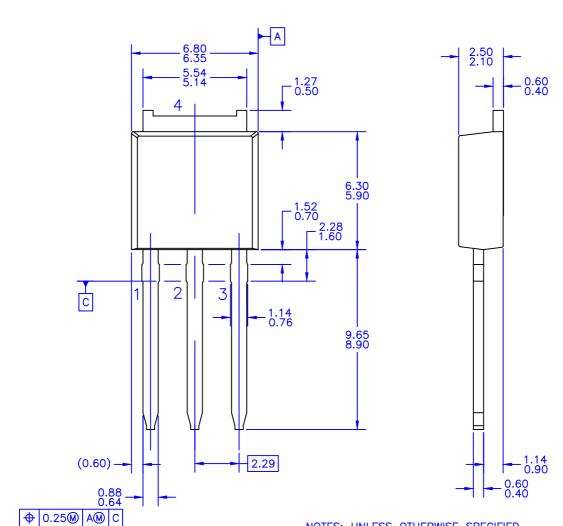
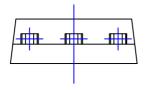


Figure 15. Peak Diode Recovery dv/dt Test Circuit & Waveforms



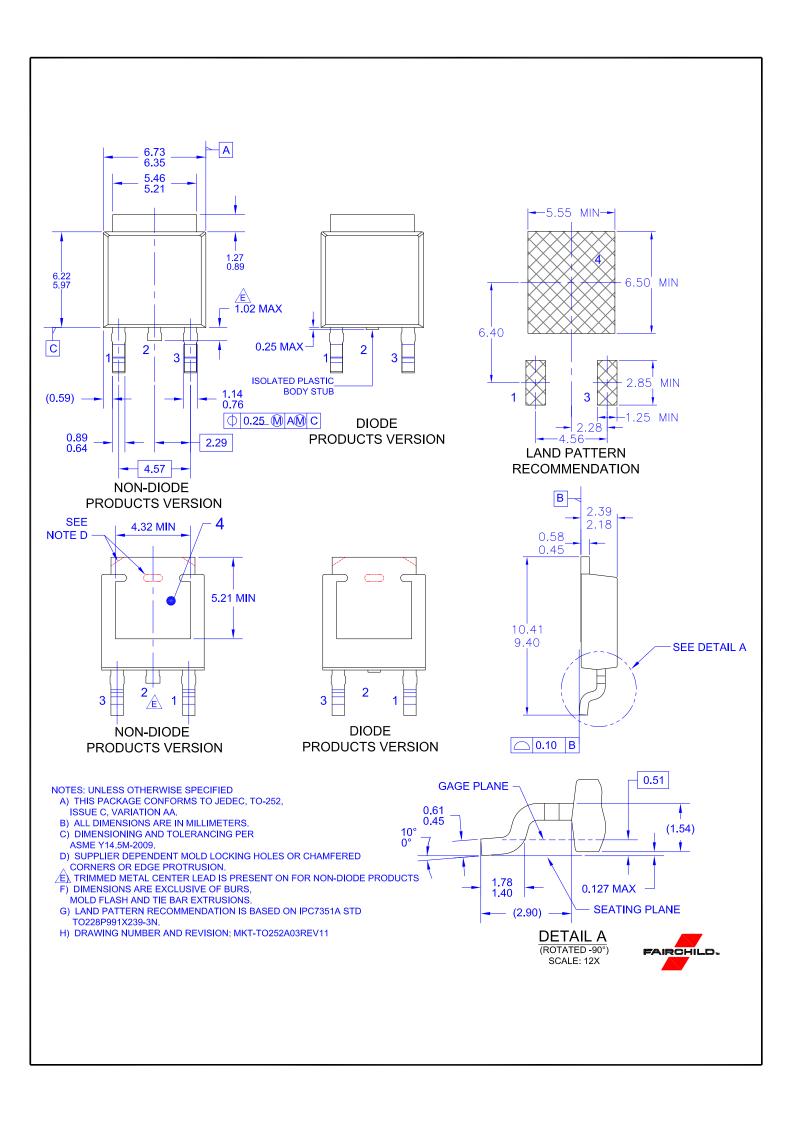


3 PLCS

- NOTES: UNLESS OTHERWISE SPECIFIED
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 - B) THIS PACKAGE CONFORMS TO JEDEC, TO-251, ISSUE C, VARIATION AA, DATED SEP 1988.
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